

5. Specification

Part Number	Inductance L0 A(uH) ±20%	I rms (A)		I sat (A)		DCR (mΩ) Typ	DCR (mΩ) Max
		Typ	Max	Typ	Max		
FMIM322512AV-R22MG	0.22	9.5	9.0	9.3	8.7	7.4	8.5
FMIM322512AV-R33MG	0.33	8.5	8.0	9.1	8.5	10.0	13.0
FMIM322512AV-R47MG	0.47	7.0	6.5	8.2	7.4	16.0	19.2
FMIM322512AV-R68MG	0.68	6.2	5.7	7.3	6.8	20.0	24.0
FMIM322512AV-1R0MG	1.00	5.5	5.0	6.5	5.7	26.0	32.0
FMIM322512AV-1R5MG	1.50	4.4	3.9	5.0	4.5	44.0	53.0
FMIM322512AV-2R2MG	2.20	4.0	3.6	4.8	4.3	61.0	73.0
FMIM322512AV-3R3MG	3.30	3.1	2.8	3.4	3.0	87.0	101.0
FMIM322512AV-4R7MG	4.70	2.2	1.9	2.8	2.4	122.0	146.0

Note:

1. Test frequency : Ls : 100KHz /1.0V.
2. All test data referenced to 25°C ambient.
3. Testing Instrument(or equ) : Agilent 4284A,E4991A,4339B,KEYSIGHT E4980A/AL,chroma3302,3250,16502.
4. Heat Rated Current (I rms) will cause the coil temperature rise approximately ΔT of 40°C
5. Saturation Current (I sat) will cause L0 to drop approximately 30%.
6. The part temperature (ambient + temp rise) should not exceed 150°C under worst case operating conditions. Circuit design, component, PCB trace size and thickness, airflow and other cooling provisions all affect the part temperature. Part temperature should be verified in the end application.
7. I rms Testing : Temperature rise is highly dependent on many factors including pcb land pattern, trace size, and proximity to other components. Therefore temperature rise should be verified in application conditions.
8. Rated DC current: The lower value of I rms and I sat.
9. Rated voltage 25V DC, The application of voltage depends on many factors, Over voltage may cause components failure, high temperature, and burn-out, User needs to verify for appropriate usage.

10. Typical Performance Curves

